

Features

- High speed: 70 ns
- Temperature ranges □ Industrial: -40 °C to +85 °C
- Voltage range: 1.65 V to 1.95 V
- Pin compatible with CY62126EV30
- Ultra low standby power
 □ Typical standby current: 1 µA
 □ Maximum standby current: 4 µA
- Ultra low active power
 Typical active current: 1.3 mA at f = 1 MHz
- Easy memory expansion with CE and OE features
- Automatic power down when deselected
- Complementary metal oxide semiconductor (CMOS) for optimum speed and power
- Offered in Pb-free 48-ball very fine-pitch ball grid array (VFBGA) package

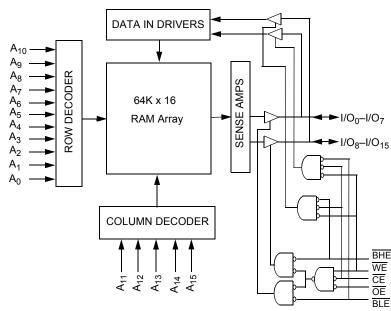
Functional Description

The CY62126EV18 is a high-performance CMOS static RAM organized as 64K words by 16 bits. This device features advanced circuit design to provide ultra low active current. This is ideal for providing More Battery LifeTM (MoBL[®]) in portable applications such as cellular telephones. The device also has an automatic power down feature that significantly reduces power consumption when addresses are not toggling. Placing the device in standby mode reduces power consumption by more than 99 percent when deselected (CE HIGH). The input and output pins (I/O₀ through I/O₁₅) are placed in a high-impedance state when the device is deselected (CE HIGH), the outputs are disabled (OE HIGH), both Byte High Enable and Byte Low Enable are disabled (BHE, BLE HIGH) or during a write operation (CE LOW and WE LOW).

To write to the device, take Chip Enable $\overline{(CE)}$ and Write Enable $\overline{(WE)}$ inputs LOW. If Byte Low Enable (BLE) is LOW, then data from I/O pins (I/O₀ through I/O₇) is written into the location specified on the address pins (A₀ through A₁₅). If Byte High Enable (BHE) is LOW, then data from I/O pins (I/O₈ through I/O₁₅) is written into the location specified on the address pins (A₀ through A₁₅).

To read <u>from</u> the device, take Chip Enable (\overline{CE}) and Output Enable (\overline{OE}) LOW <u>while</u> forcing the Write Enable (WE) HIGH. If Byte Low Enable (BLE) is LOW, then data from the memory location specified by <u>the</u> address pins appear on I/O₀ to I/O₇. If Byte High Enable (BHE) is LOW, then data from memory appears on I/O₈ to I/O₁₅. See the Truth Table on page 11 for a complete description of read and write modes.

Logic Block Diagram



San Jose, CA 95134-1709
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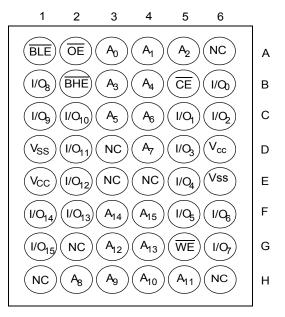
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Pin Configuration

Figure 1. 48-ball VFBGA Pinout (Top View)



Product Portfolio

		Power Dissipati				sipation	n				
Product Range		V _{CC} Range (V)		Speed	Operating, I _{CC} (mA)			Standby, I _{SB2}			
Floudel	Kange				(ns)	f = 1	f = 1 MHz f = f _{max}		(μ Ă	(μÅ)	
		Min	Typ ^[2]	Max		Typ ^[2]	Max	Typ ^[2]	Max	Typ ^[2]	Max
CY62126EV18LL	Industrial	1.65	1.8	1.95	70	1.3	2	11	12	1	4

Notes

NC pins are not connected on the die.
 Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at V_{CC} = V_{CC(typ)}, T_A = 25 °C.



Maximum Ratings

Exceeding maximum ratings may shorten the battery life of the device. These user guidelines are not tested.

Storage temperature65 °C to +150 °C
Ambient temperature with power applied–55 °C to +125 °C
Supply voltage to ground potential ^[3, 4] –0.3 V to 2.25 V (V _{CCmax} + 0.3 V)
DC voltage applied to outputs in High Z state $^{[3,\;4]}$ 0.3 V to 2.25 V (V $_{CCmax}$ + 0.3 V)

DC input voltage $^{[3, 4]}$ –0.3 V to 2.25 V (V _{CCma}	_{ax} + 0.3 V)
Output current into outputs (LOW)	20 mA
Static discharge voltage (MIL-STD-883, Method 3015)	> 2001 V
Latch-up current	> 200 mA

Operating Range

Device	Range	Ambient Temperature	V_{CC^[5]}
CY62126EV18LL	Industrial	–40 °C to +85 °C	1.65 V to 1.95 V

Electrical Characteristics

Over the Operating Range

Damanatan	Description	Tast Osmalitisms			70 n	S	11
Parameter	Description	Test Conditions		Min	Typ ^[6]	Max	Unit
V _{OH}	Output high voltage	I _{OH} = -0.1 mA		1.4	-	_	V
V _{OL}	Output low voltage	I _{OL} = 0.1 mA		-	-	0.2	V
V _{IH}	Input high voltage	V _{CC} = 1.65 V to 1.95 V		1.4	-	V _{CC} + 0.2 V	V
V _{IL}	Input low voltage	V _{CC} = 1.65 V to 1.95 V		-0.2	-	0.4	V
I _{IX}	Input leakage current	$GND \leq V_I \leq V_{CC}$		-1	-	+1	μΑ
I _{OZ}	Output leakage current	$GND \leq V_O \leq V_{CC}$, Output Disabled		-1	-	+1	μA
I _{CC}	V _{CC} operating supply current	$f = f_{max} = 1/t_{RC}$	V _{CC} = V _{CCmax} I _{OUT} = 0 mA CMOS levels	-	11	12	mA
		f = 1 MHz		-	1.3	2.0	
I _{SB1} ^[7]	Automatic CE power down current —CMOS inputs	$\label{eq:central_constraints} \begin{split} \overline{CE} &\geq V_{CC} - 0.2 \text{ V}, \\ V_{IN} &\geq V_{CC} - 0.2 \text{ V}, \text{ V}_{IN} \leq 0.2 \text{ V}, \\ f &= f_{max} \text{ (Address and Data Only),} \\ f &= 0 \text{ (OE, BHE, BLE, and WE),} \\ V_{CC} &= 1.95 \text{ V} \end{split}$		_	1	4	μA
I _{SB2} ^[7]	Automatic CE power down current —CMOS inputs	$\label{eq:central_constraint} \begin{split} \overline{CE} &\geq V_{CC} - 0.2 \text{ V}, \\ V_{IN} &\geq V_{CC} - 0.2 \text{ V or } V_{IN} \leq 0.2 \text{ V}, \\ f &= 0, \ V_{CC} = 1.95 \text{ V} \end{split}$		-	1	4	μΑ

Notes

- Notes
 3. V_{IL(min)} = -2.0 V for pulse durations less than 20 ns.
 4. V_{IH(max)} = V_{CC} + 0.75 V for pulse durations less than 20 ns.
 5. Full device AC operation assumes a 100 μs ramp time from 0 to V_{cc}(min) and 200 μs wait time after V_{cc} stabilization.
 6. Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at V_{CC} = V_{CC(typ)}, T_A = 25 °C.
 7. Chip enable (CE) needs to be tied to CMOS levels to meet the I_{SB1} / I_{SB2} / I_{CCDR} spec. Other inputs can be left floating.



Capacitance

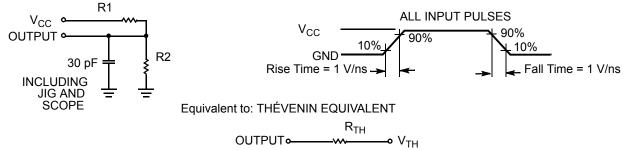
Parameter ^[8]	Description	Test Conditions	Мах	Unit
C _{IN}	Input capacitance	$T_A = 25 \text{ °C, } f = 1 \text{ MHz, } V_{CC} = V_{CC(typ)}$	10	pF
C _{OUT}	Output capacitance		10	pF

Thermal Resistance

Parameter ^[8]	Description	Test Conditions	48-ball VFBGA Package	Unit
Θ_{JA}	Thermal resistance (junction to ambient)	Still Air, soldered on a 4.25 × 1.125 inch, two-layer printed circuit board	58.85	°C/W
Θ ^{JC}	Thermal resistance (junction to case)		17.01	°C/W

AC Test Loads and Waveforms





Parameters	1.65 V–1.95 V	Unit
R1	13500	Ω
R2	10800	Ω
R _{TH}	6000	Ω
V _{TH}	0.8	V



Data Retention Characteristics

Over the Operating Range

Parameter	Description	Conc	litions	Min	Typ ^[9]	Max	Unit
V _{DR}	V_{CC} for data retention			1	-	-	V
I _{CCDR} ^[10]	Data retention current	$V_{CC} = V_{DR},$	Industrial			3	μA
		$\label{eq:cell} \begin{split} \overline{CE} &\geq V_{CC} - 0.2 \text{ V}, \\ V_{IN} &\geq V_{CC} - 0.2 \text{ V or} \\ V_{IN} &\leq 0.2 \text{ V} \end{split}$	industrial	_	_	5	
t _{CDR} ^[11]	Chip deselect to data retention time			0	-	_	ns
t _R ^[12]	Operation recovery time			70	_	_	ns

Data Retention Waveform





Notes

9. Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at $V_{CC} = V_{CC(typ)}$, $T_A = 25$ °C. 10. Chip enable (CE) needs to be tied to CMOS levels to meet the $I_{SB1} / I_{SB2} / I_{CCDR}$ spec. Other inputs can be left floating. 11. Tested initially and after any design or process changes that may affect these parameters. 12. Full device AC operation requires linear V_{CC} ramp from V_{DR} to $V_{CC(min)} > 100 \ \mu$ s.



Switching Characteristics

Over the Operating Range

Parameter ^[13]	Description	70	70 ns		
	Description	Min	Max	Unit	
Read Cycle	•			•	
t _{RC}	Read cycle time	70	-	ns	
t _{AA}	Address to data valid	-	70	ns	
t _{OHA}	Data hold from address change	10	_	ns	
t _{ACE}	CE LOW to data valid	-	70	ns	
t _{DOE}	OE LOW to data valid	-	35	ns	
t _{LZOE}	OE LOW to Low Z ^[14]	5	-	ns	
t _{HZOE}	OE HIGH to High Z ^[14, 15]	-	25	ns	
t _{LZCE}	CE LOW to Low Z ^[14]	10	-	ns	
t _{HZCE}	CE HIGH to High Z [14, 15]	-	25	ns	
t _{PU}	CE LOW to power up	0	_	ns	
t _{PD}	CE HIGH to power down	-	70	ns	
t _{DBE}	BHE / BLE LOW to data valid	-	35	ns	
t _{LZBE}	BHE / BLE LOW to Low Z ^[14]	5	-	ns	
t _{HZBE}	BHE / BLE HIGH to High Z ^[14, 15]	-	25	ns	
Write Cycle [16, 17]			·		
t _{WC}	Write cycle time	70	-	ns	
t _{SCE}	CE LOW to write end	60	-	ns	
t _{AW}	Address setup to write end	60	-	ns	
t _{HA}	Address hold from write end	0	-	ns	
t _{SA}	Address setup to write start	0	-	ns	
t _{PWE}	WE pulse width	60	-	ns	
t _{BW}	BHE / BLE pulse width	60	-	ns	
t _{SD}	Data setup to write end	35	-	ns	
t _{HD}	Data hold from write end	0	-	ns	
t _{HZWE}	WE LOW to High Z ^[14, 15]	-	25	ns	
t _{LZWE}	WE HIGH to Low Z ^[14]	10	-	ns	

Notes

13. Test conditions assume signal transition time of 1.8 ns or less, timing reference levels of V_{CC(typ}/2, input pulse levels of 0 to V_{CC(typ}), and output loading of the specified I_{OL}/I_{OH} and 30-pF load capacitance.

14. At any temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZBE} is less than t_{LZDE}, t_{HZOE} is less than t_{LZDE}, and t_{HZWE} is less than t_{LZWE} for any device.
15. t_{HZOE}, t_{HZCE}, t_{HZDE}, t_{HZDE}, t_{HZDE}, t_{HZDE} is less than t_{LZWE} transitions are measured when the outputs enter a high impedance state.
16. The internal write time of the memory is defined by the overlap of WE, CE = V_{IL}, BHE, BLE or both = V_{IL}. All signals must be active to initiate a write and any of these signals can terminate a write by going inactive. The data input setup and hold timing must refer to the edge of signal that terminates write.
17. The minimum write cycle pulse width for Write Cycle No. 3 (WE Controlled, OE LOW) should be equal to sum of t_{SD} and t_{HZWE}.



Switching Waveforms

Figure 4. Read Cycle No. 1 (Address transition controlled) ^[18, 19]

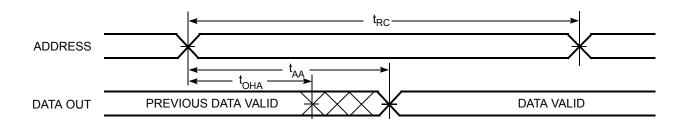
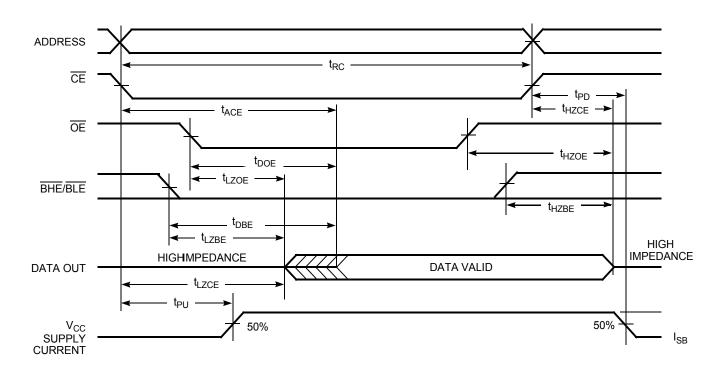


Figure 5. Read Cycle No. 2 (OE controlled) ^[19, 20]



Notes

18. <u>The</u> device is continuously selected. \overline{OE} , $\overline{CE} = V_{IL}$, \overline{BHE} , \overline{BLE} , or both = V_{IL} . 19. WE is high for read cycle. 20. Address valid before or similar to \overline{CE} and \overline{BHE} , \overline{BLE} transition LOW.





Switching Waveforms (continued)

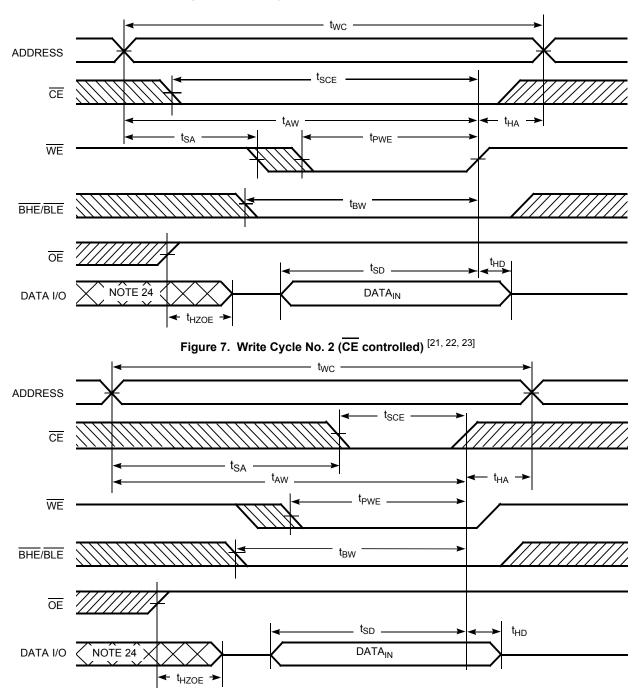


Figure 6. Write Cycle No. 1 ($\overline{\text{WE}}$ controlled) [21, 22, 23]

Notes

- 21. The internal write time of the memory is defined by the overlap of \overline{WE} , $\overline{CE} = V_{IL}$, \overline{BHE} , \overline{BLE} or both = V_{IL} . All signals must be active to initiate a write and any of these signals can terminate a write by going inactive. The data input setup and hold timing must refer to the edge of signal that terminates write. 22. Data I/O is high impedance if $\overline{OE} = V_{IH}$. 23. If \overline{CE} goes high simultaneously with $\overline{WE} = V_{IH}$, the output remains in a high impedance state. 24. During this period, the I/Os are in output state. Do not apply input signals.





Switching Waveforms (continued)

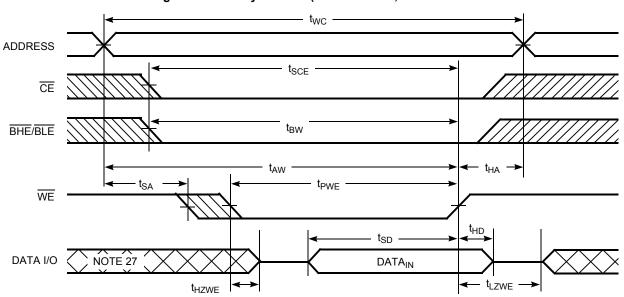
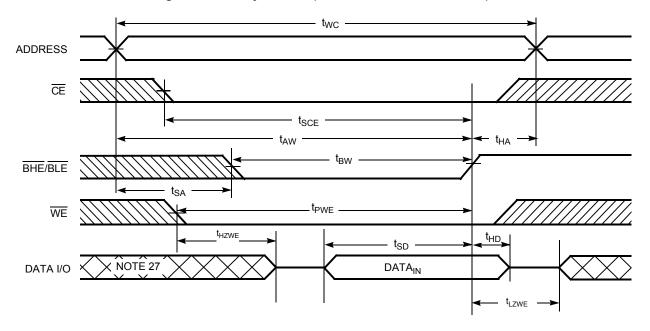


Figure 8. Write Cycle No. 3 (WE controlled, OE LOW ^[25, 26]

Figure 9. Write Cycle No. 4 ($\overline{\text{BHE}}/\overline{\text{BLE}}$ controlled, $\overline{\text{OE}}$ LOW) [25]



Notes

25. If \overline{CE} goes high simultaneously with $\overline{WE} = V_{IH}$, the output remains in a high impedance state. 26. The minimum write cycle pulse width should be equal to sum of t_{SD} and t_{HZWE} . 27. During this period, the I/Os are in output state. Do not apply input signals.





Truth Table

CE ^[28]	WE	OE	BHE	BLE	Inputs/Outputs	Mode	Power
Н	Х	Х	Х	Х	High Z	Deselect/power down	Standby (I _{SB})
L	Х	Х	Н	Н	High Z	Output disabled	Active (I _{CC})
L	Н	L	L	L	Data out (I/O ₀ –I/O ₁₅)	Read	Active (I _{CC})
L	Н	L	Н	L	Data out (I/O ₀ –I/O ₇); I/O ₈ –I/O ₁₅ in High Z	Read	Active (I _{CC})
L	Н	L	L	Н	Data out (I/O ₈ –I/O ₁₅); I/O ₀ –I/O ₇ in High Z	Read	Active (I _{CC})
L	Н	Н	L	L	High Z	Output disabled	Active (I _{CC})
L	Н	Н	Н	L	High Z	Output disabled	Active (I _{CC})
L	Н	Н	L	Н	High Z	Output disabled	Active (I _{CC})
L	L	Х	L	L	Data in (I/O ₀ –I/O ₁₅)	Write	Active (I _{CC})
L	L	Х	Н	L	Data in (I/O ₀ –I/O ₇); I/O ₈ –I/O ₁₅ in High Z	Write	Active (I _{CC})
L	L	Х	L	Н	Data in (I/O ₈ –I/O ₁₅); I/O ₀ –I/O ₇ in High Z	Write	Active (I _{CC})

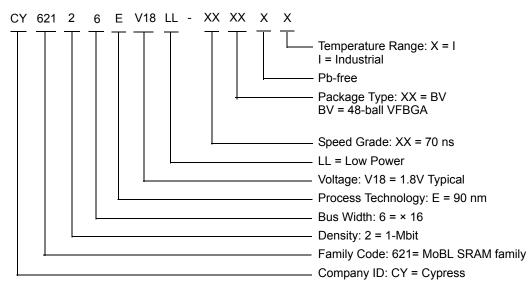


Ordering Information

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
70	CY62126EV18LL-70BVXI	51-85150	48-ball VFBGA (Pb-free)	Industrial

Contact your local Cypress sales representative for availability of other parts.

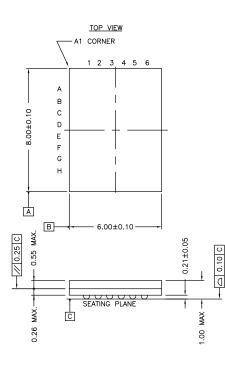
Ordering Code Definitions

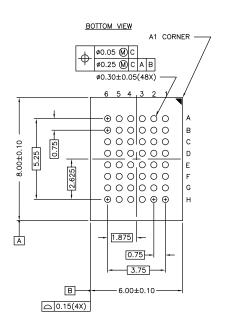




Package Diagram

Figure 10. 48-ball VFBGA (6 × 8 × 1.0 mm) Package Outline, 51-85150





NOTE: PACKAGE WEIGHT: See Cypress Package Material Declaration Datasheet (PMDD) posted on the Cypress web.

51-85150 *H



Acronyms

Acronym	Description
CE	Chip Enable
CMOS	Complementary Metal Oxide Semiconductor
I/O	Input/Output
OE	Output Enable
RAM	Random Access Memory
SRAM	Static Random Access Memory
TSOP	Thin Small Outline Package
VFBGA	Very Fine-Pitch Ball Grid Array
WE	Write Enable

Document Conventions

Units of Measure

Symbol	Unit of Measure
°C	degree Celsius
MHz	megahertz
μA	microampere
μs	microsecond
mA	milliampere
mm	millimeter
ns	nanosecond
Ω	ohm
%	percent
pF	picofarad
V	volt
W	watt



Document History Page

Document Title: CY62126EV18 MoBL [®] , 1-Mbit (64 K × 16) Static RAM Document Number: 001-94739				
Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change
**	4547224	VINI	11/07/2014	New datasheet.
*A	5536310	VINI	11/29/2016	Changed datasheet status to Final. Updated template.
*В	6013631	AESATMP9	01/04/2018	Updated logo and copyright.



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